

----- Group:Common preparations-----

Vampset: Adapted frequency off (50Hz)

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	08-joulu-2014 09:48:31	Test End:	08-joulu-2014 09:48:43
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

----- Group end:Common preparations-----

----- Group:265 Sn.xxxx personal preparations-----

Vampset: CT&VT settings + output matrix

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	08-joulu-2014 09:51:01	Test End:	08-joulu-2014 09:53:54
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

----- Group end:265 Sn.xxxx personal preparations-----

Hardware Configuration

Test Equipment

Type	Serial Number
CMC356	HE344P

Hardware Check

Performed At	Result	Details
8.12.2014 14:41:33	Passed	

----- Group:Earth fault stage Io> (50N/51N)-----

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io1CT=5A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 12:14:50
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 12:15:07
Manager:

Vampset: 50N/51N

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 12:16:58
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 12:18:38
Manager:

Test Settings

General

No. of ramp states: 6
Total steps per test: 506
Total time per test: 27,200
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	50,00 mA -9,00 ° 50,000 Hz	50,00 mA -9,00 ° 50,000 Hz	200,0 mA -9,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	2,100 A 172,00 ° 50,000 Hz

Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	50,00 mA	50,00 mA	200,0 mA	1,800 A	1,800 A	2,100 A
Sig 1 To	50,00 mA	200,0 mA	50,00 mA	1,800 A	2,100 A	1,800 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	3,000 mA	-3,000 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	60,00 mA/s	-60,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
 Test Start: 08-joulu-2014 12:27:32
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 12:27:33
 Manager:

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'1	100,0 mA	108,0 mA	10,00 mA	10,00 mA	8,000 mA	+	500,0
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'1	95,00 mA	100,0 mA	10,00 mA	10,00 mA	5,000 mA	+	24,10
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'1	2,000 A	2,001 A	30,00 mA	30,00 mA	1,000 mA	+	39,30
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'1	1,900 A	1,899 A	30,00 mA	30,00 mA	-1,000 mA	+	20,20

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
 Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'1	0,000 A 0,00 ° 50,000 Hz	160,0 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	40,00 mA 172,00 ° 50,000 Hz	2,045 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'1	40,00 mA -7,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz						

Test Module

Name: OMICRON State Sequencer
 Test Start: 08-joulu-2014 10:04:44
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 10:04:45
 Manager:

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	49,30 ms	19,30 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	52,90 ms	12,90 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,90 ms	-57,10 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,20 ms	-57,80 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	48,50 ms	18,50 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,012 s	11,80 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,10 ms	-56,90 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,30 ms	-57,70 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	No trip after boot (Grp2)						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io2CT=5A
 Device type:
 Serial/model number:
 Additional info 1:
 Additional info 2:

Manufacturer:
 Device address:

Vampset: Disable stages**Test State:**

Command executed
 Test passed

Test Module

Name: OMICRON ExeCute
 Test Start: 08-joulu-2014 10:07:03
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 10:07:19
 Manager:

Vampset: 50N/51N**Test State:**

Command executed
 Test passed

Test Module

Name: OMICRON ExeCute
 Test Start: 08-joulu-2014 10:09:36
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 10:11:17
 Manager:

Test Settings**General**

No. of ramp states: 6
 Total steps per test: 506
 Total time per test: 27,200
 No. of test executions: 1

Input Mode: Direct
 Fault Type:

Ramped Quantities

I² / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I ²	50,00 mA -7,00 ° 50,000 Hz	50,00 mA -7,00 ° 50,000 Hz	200,0 mA -7,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	2,100 A 172,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	50,00 mA	50,00 mA	200,0 mA	1,800 A	1,800 A	2,100 A
Sig 1 To	50,00 mA	200,0 mA	50,00 mA	1,800 A	2,100 A	1,800 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	3,000 mA	-3,000 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	60,00 mA/s	-60,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	None	Bin	None	None	Bin
Trigger Logic			OR			OR

Start (A1)			0			0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping Version: 3.00 SR 2
 Test Start: 08-joulu-2014 10:13:10 Test End: 08-joulu-2014 10:13:11
 User Name: Jesse Saastamoinen Manager:
 Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	100,0 mA	100,0 mA	10,00 mA	10,00 mA	0,000 A	+	11,60
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	95,00 mA	93,00 mA	10,00 mA	10,00 mA	-2,000 mA	+	34,00
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	2,000 A	2,019 A	30,00 mA	30,00 mA	19,00 mA	+	4,400
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	1,900 A	1,911 A	30,00 mA	30,00 mA	11,00 mA	+	29,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'2	0,000 A 0,00 ° 50,000 Hz	160,0 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	40,00 mA 172,00 ° 50,000 Hz	2,045 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'2	40,00 mA -7,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz						

Test Module

Name: OMICRON State Sequencer Version: 3.00 SR 2
 Test Start: 08-joulu-2014 10:15:32 Test End: 08-joulu-2014 10:15:32
 User Name: Jesse Saastamoinen Manager:
 Company: Schneider Electric - Vamp

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	45,30 ms	15,30 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	49,40 ms	9,400 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,50 ms	-57,50 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	36,70 ms	-58,30 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,40 ms	28,40 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,90 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,00 ms	-57,00 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,10 ms	-57,90 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	No trip after boot (Grp2)						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: IoCalcCT=5A
 Device type:
 Serial/model number:
 Additional info 1:
 Additional info 2:

Manufacturer:
 Device address:

Vampset: Disable stages**Test State:**

Command executed
 Test passed

Test Module

Name: OMICRON ExeCute
 Test Start: 08-joulu-2014 12:36:46
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 12:37:02
 Manager:

Vampset: 50N/51N**Test State:**

Command executed
 Test passed

Test Module

Name: OMICRON ExeCute
 Test Start: 08-joulu-2014 12:38:53
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 12:40:33
 Manager:

Test Settings**General**

No. of ramp states: 9
 Total steps per test: 1077
 Total time per test: 56,700
 No. of test executions: 1

Input Mode: Direct
 Fault Type:

Ramped Quantities

I 3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6	Ramp 7	Ramp 8
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000
I 2	5,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000
I 3	5,150 A 120,00 ° 50,000 Hz	5,150 A 120,00 ° 50,000 Hz	5,350 A 120,00 ° 50,000 Hz	7,500 A 120,00 ° 50,000 Hz	7,500 A 120,00 ° 50,000 Hz	8,500 A 120,00 ° 50,000 Hz	10,00 A 120,00 ° 50,000 Hz	10,00 A 120,00 ° 50,000
Force abs. Phases	Yes	Yes	Yes	Yes	Yes	Yes	No	No
Sig 1 From	5,150 A	5,150 A	5,350 A	7,500 A	7,500 A	8,500 A	10,00 A	10,00 A
Sig 1 To	5,150 A	5,350 A	5,150 A	7,500 A	8,500 A	5,000 A	10,00 A	11,50 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	12,00 mA	-12,00 mA	0,000 A	12,00 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	240,0 mA/s	-240,0 mA/s	0,000 A/s	240,0

DI1	0	0	0	1	1	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms
Ramp Steps	1	201	201	1	85	293	1	126
Ramp Time	1,000s	10,050s	10,050s	1,000s	4,250s	14,650s	1,000s	6,300s
Trigger	None	None	Bin	None	None	Bin	None	None
Trigger Logic Start (A1)			OR 0			OR 0		
Step back	No	No	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s
Ramp	Ramp 9							
I 1	5,000 A 0,00 ° 50,000 Hz							
I 2	5,000 A -30,00 ° 50,000 Hz							
I 3	11,50 A 120,00 ° 50,000 Hz							
Force abs. Phases	No							
Sig 1 From	11,50 A							
Sig 1 To	9,500 A							
Sig 1 Delta	-12,00 mA							
Sig 1 d/dt	-240,0 mA/s							
DI1	1							
dt per Step	50,00 ms							
Ramp Steps	168							
Ramp Time	8,400s							
Trigger	Bin							
Trigger Logic Start (A1)	OR 0							
Step back	No							
Delay Time	0,000 s							

Test Module

Name: OMICRON Ramping
Test Start: 08-joulu-2014 13:42:18
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version:
Test End:
Manager:

3.00 SR 2
08-joulu-2014 13:42:34

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	5,250 A	5,240 A	10,00 mA	10,00 mA	-10,00 mA	+	46,50
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	5,237 A	5,228 A	10,00 mA	10,00 mA	-9,500 mA	+	25,10
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 3	8,000 A	8,016 A	120,0 mA	120,0 mA	16,00 mA	+	3,500
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 3	7,600 A	7,600 A	120,0 mA	120,0 mA	0,000 A	+	41,30
Pick-up (Grp2)	Ramp 8	Start (A1) 0->1	I 3	11,00 A	10,98 A	120,0 mA	120,0 mA	-16,00 mA	+	23,80
Drop-off (Grp2)	Ramp 9	Start (A1) 1->0	I 3	10,16 A	10,12 A	120,0 mA	120,0 mA	-45,00 mA	+	15,80

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	8,165 A 0,00 ° 50,000 Hz	7,440 A 0,00 ° 50,000 Hz	7,440 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz
I 2	5,000 A -120,00 ° 50,000 Hz	5,265 A -120,00 ° 50,000 Hz	5,225 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz
I 3	5,000 A 120,00 ° 50,000 Hz	5,000 A 120,00 ° 50,000 Hz	5,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	5,225 A 120,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz						
I 2	5,000 A -120,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000 Hz						
I 3	5,225 A 120,00 ° 50,000 Hz	9,790 A 120,00 ° 50,000 Hz						

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	08-joulu-2014 12:44:34	Test End:	08-joulu-2014 12:44:34
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	53,10 ms	23,10 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	56,90 ms	16,90 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	27,80 ms	-67,20 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	27,10 ms	-67,90 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,40 ms	28,40 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,80 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,10 ms	-56,90 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,40 ms	-57,60 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	No trip after boot (Grp2)						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

-----Group end:IoCT 5A & 5A (265&265M)-----

-----Group:IoCT 1A & 1A (265&265M)-----

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io1CT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io2CT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed

Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 14:47:51
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 14:48:08
Manager:

Vampset: 50N/51N

Test State:

Command executed

Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 14:50:01
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 14:51:41
Manager:

Test Settings

General

No. of ramp states: 6
Total steps per test: 506
Total time per test: 27,200
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I² / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I ²	10,00 mA -7,00 ° 50,000 Hz	10,00 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	360,0 mA 172,00 ° 50,000 Hz	360,0 mA 172,00 ° 50,000 Hz	420,0 mA 172,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	10,00 mA	10,00 mA	40,00 mA	360,0 mA	360,0 mA	420,0 mA
Sig 1 To	10,00 mA	40,00 mA	10,00 mA	360,0 mA	420,0 mA	360,0 mA
Sig 1 Delta	0,000 A	200,0 µA	-200,0 µA	0,000 A	600,0 µA	-600,0 µA
Sig 1 d/dt	0,000 A/s	4,000 mA/s	-4,000 mA/s	0,000 A/s	12,00 mA/s	-12,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Test Start: 08-joulu-2014 16:34:29
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 16:34:29
Manager:

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	20,00 mA	21,20 mA	2,000 mA	2,000 mA	1,200 mA	+	13,50
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	19,00 mA	19,80 mA	2,000 mA	2,000 mA	800,0 µA	+	44,70
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	400,0 mA	399,0 mA	6,000 mA	6,000 mA	-1,000 mA	+	40,60
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	380,0 mA	378,0 mA	6,000 mA	6,000 mA	-2,000 mA	+	21,10

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'2	0,000 A -120,00 ° 50,000 Hz	32,00 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz	409,0 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'2	8,000 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz						

Test Module

Name: OMICRON State Sequencer
 Test Start: 08-joulu-2014 16:44:01
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 16:44:02
 Manager:

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	47,20 ms	17,20 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	51,00 ms	11,00 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,80 ms	-57,20 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,10 ms	-57,90 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,40 ms	28,40 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,70 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,10 ms	-56,90 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,40 ms	-57,60 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	No trip after boot (Grp2)						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: loCalcCT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

-----Group end:loCT 1A & 1A (265&265M)-----
-----Group end:Earth fault stage lo> (50N/51N)-----
-----Group:Earth fault stage lo>> (50N/51N)-----

-----Group:loCT 5A & 5A (265&265M)-----

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: lo1CT=5A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:03:05
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:03:22
Manager:

Vampset: 50N/51N

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:05:39
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:07:19
Manager:

Test Settings

General

No. of ramp states: 6
 Total steps per test: 506
 Total time per test: 27,200
 No. of test executions: 1

Input Mode: Direct
 Fault Type:

Ramped Quantities

I'1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	50,00 mA -9,00 ° 50,000 Hz	50,00 mA -9,00 ° 50,000 Hz	200,0 mA -9,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	2,100 A 172,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	50,00 mA	50,00 mA	200,0 mA	1,800 A	1,800 A	2,100 A
Sig 1 To	50,00 mA	200,0 mA	50,00 mA	1,800 A	2,100 A	1,800 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	3,000 mA	-3,000 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	60,00 mA/s	-60,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping Version: 3.00 SR 2
 Test Start: 08-joulu-2014 11:09:39 Test End: 08-joulu-2014 11:09:39
 User Name: Jesse Saastamoinen Manager:
 Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'1	100,0 mA	109,0 mA	10,00 mA	10,00 mA	9,000 mA	+	7,200
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'1	95,00 mA	103,0 mA	10,00 mA	10,00 mA	8,000 mA	+	29,20
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'1	2,000 A	2,001 A	30,00 mA	30,00 mA	1,000 mA	+	44,60
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'1	1,900 A	1,899 A	30,00 mA	30,00 mA	-1,000 mA	+	37,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'1	0,000 A 0,00 ° 50,000 Hz	160,0 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	40,00 mA 172,00 ° 50,000 Hz	2,045 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'1	40,00 mA -7,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz						

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	08-joulu-2014 11:12:00	Test End:	08-joulu-2014 11:12:00
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	51,70 ms	21,70 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	55,50 ms	15,50 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,80 ms	-57,20 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,00 ms	-58,00 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,30 ms	28,30 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,60 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,20 ms	-56,80 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,50 ms	-57,50 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0

	Cold boot #2	No trip after boot (Grp2)							
Assess	+	+							
Tolerance	0,000 s	0,000 s							
Start (A1)	0	0							
Trip (T1)	0	0							

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io2CT=5A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:14:18
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:14:35
Manager:

Vampset: 50N/51N

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:16:52
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:18:32
Manager:

Test Settings

General

No. of ramp states: 6
Total steps per test: 506
Total time per test: 27,200
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'2 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'2	50,00 mA -7,00 ° 50,000 Hz	50,00 mA -7,00 ° 50,000 Hz	200,0 mA -7,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	1,800 A 172,00 ° 50,000 Hz	2,100 A 172,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	50,00 mA	50,00 mA	200,0 mA	1,800 A	1,800 A	2,100 A
Sig 1 To	50,00 mA	200,0 mA	50,00 mA	1,800 A	2,100 A	1,800 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	3,000 mA	-3,000 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	60,00 mA/s	-60,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	None	Bin	None	None	Bin
Trigger Logic			OR			OR
Start (A1)			0			0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Test Start: 08-joulu-2014 11:20:52
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:20:53
Manager:

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	100,0 mA	99,00 mA	10,00 mA	10,00 mA	-1,000 mA	+	46,60
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	95,00 mA	93,00 mA	10,00 mA	10,00 mA	-2,000 mA	+	24,90
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	2,000 A	2,019 A	30,00 mA	30,00 mA	19,00 mA	+	0,000 s
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	1,900 A	1,911 A	30,00 mA	30,00 mA	11,00 mA	+	13,60

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'2	0,000 A 0,00 ° 50,000 Hz	160,0 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	40,00 mA 172,00 ° 50,000 Hz	2,045 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'2	40,00 mA -7,00 ° 50,000 Hz	1,855 A 172,00 ° 50,000 Hz						

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	08-joulu-2014 11:23:14	Test End:	08-joulu-2014 11:23:14
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	48,70 ms	18,70 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	52,50 ms	12,50 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,70 ms	-57,30 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,10 ms	-57,90 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,50 ms	28,50 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,90 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,90 ms	-57,10 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,10 ms	-57,90 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0

	Cold boot #2	No trip after boot (Grp2)							
Assess	+	+							
Tolerance	0,000 s	0,000 s							
Start (A1)	0	0							
Trip (T1)	0	0							

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: IoCalcCT=5A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:25:31
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:25:48
Manager:

Vampset: 50N/51N

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 11:28:05
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 11:29:45
Manager:

Test Settings

General

No. of ramp states: 9
 Total steps per test: 1077
 Total time per test: 56,700
 No. of test executions: 1

Input Mode: Direct
 Fault Type:

Ramped Quantities

I 3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6	Ramp 7	Ramp 8
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000
I 2	5,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000
I 3	<u>5,150 A</u> 120,00 ° 50,000 Hz	<u>5,150 A</u> 120,00 ° 50,000 Hz	<u>5,350 A</u> 120,00 ° 50,000 Hz	<u>7,500 A</u> 120,00 ° 50,000 Hz	<u>7,500 A</u> 120,00 ° 50,000 Hz	<u>8,500 A</u> 120,00 ° 50,000 Hz	<u>10,00 A</u> 120,00 ° 50,000 Hz	<u>10,00 A</u> 120,00 ° 50,000
Force abs. Phases	Yes	No	No	No	No	No	No	No
Sig 1 From	5,150 A	5,150 A	5,350 A	7,500 A	7,500 A	8,500 A	10,00 A	10,00 A
Sig 1 To	5,150 A	5,350 A	5,150 A	7,500 A	8,500 A	5,000 A	10,00 A	11,50 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	12,00 mA	-12,00 mA	0,000 A	12,00 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	240,0 mA/s	-240,0 mA/s	0,000 A/s	240,0
DI1	0	0	0	1	1	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms
Ramp Steps	1	201	201	1	85	293	1	126
Ramp Time	1,000s	10,050s	10,050s	1,000s	4,250s	14,650s	1,000s	6,300s
Trigger	None	None	Bin	None	None	Bin	None	None
Trigger Logic Start (A1)			OR 0			OR 0		
Step back Delay Time	No 0,000 s	No 0,000 s	No 0,000 s	No 0,000 s	No 0,000 s	No 0,000 s	No 0,000 s	No 0,000 s
Ramp	Ramp 9							
I 1	5,000 A 0,00 ° 50,000 Hz							
I 2	5,000 A -30,00 ° 50,000 Hz							
I 3	<u>11,50 A</u> 120,00 ° 50,000 Hz							
Force abs. Phases	No							
Sig 1 From	11,50 A							
Sig 1 To	9,500 A							
Sig 1 Delta	-12,00 mA							
Sig 1 d/dt	-240,0 mA/s							
DI1	1							
dt per Step	50,00 ms							
Ramp Steps	168							
Ramp Time	8,400s							
Trigger	Bin							
Trigger Logic Start (A1)	OR 0							
Step back Delay Time	No 0,000 s							

Test Module

Name: OMICRON Ramping
 Test Start: 08-joulu-2014 11:32:05
 User Name: Jesse Saastamoinen
 Company: Schneider Electric - Vamp

Version: 3.00 SR 2
 Test End: 08-joulu-2014 11:32:22
 Manager:

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	5,250 A	5,240 A	10,00 mA	10,00 mA	-10,00 mA	+	38,20
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	5,237 A	5,229 A	10,00 mA	10,00 mA	-8,500 mA	+	19,70
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 3	8,000 A	8,004 A	120,0 mA	120,0 mA	4,000 mA	+	48,10
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 3	7,600 A	7,600 A	120,0 mA	120,0 mA	0,000 A	+	34,60
Pick-up (Grp2)	Ramp 8	Start (A1) 0->1	I 3	11,00 A	10,97 A	120,0 mA	120,0 mA	-28,00 mA	+	35,70
Drop-off (Grp2)	Ramp 9	Start (A1) 1->0	I 3	10,16 A	10,13 A	120,0 mA	120,0 mA	-33,00 mA	+	38,30

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
 Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz	0,000 A 0,00 ° 50,000 Hz	8,165 A 0,00 ° 50,000 Hz	7,440 A 0,00 ° 50,000 Hz	7,440 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz
I 2	5,000 A -120,00 ° 50,000 Hz	5,265 A -120,00 ° 50,000 Hz	5,225 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	0,000 A -120,00 ° 50,000 Hz	5,000 A -120,00 ° 50,000 Hz
I 3	5,000 A 120,00 ° 50,000 Hz	5,000 A 120,00 ° 50,000 Hz	5,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	0,000 A 120,00 ° 50,000 Hz	5,225 A 120,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I 1	5,000 A 0,00 ° 50,000 Hz	5,000 A 0,00 ° 50,000 Hz						
I 2	5,000 A -120,00 ° 50,000 Hz	5,000 A -30,00 ° 50,000 Hz						
I 3	5,225 A 120,00 ° 50,000 Hz	9,790 A 120,00 ° 50,000 Hz						

Test Module

Name: OMICRON State Sequencer
 Test Start: 08-joulu-2014 11:34:43

Version: 3.00 SR 2
 Test End: 08-joulu-2014 11:34:43

User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Manager:

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	57,80 ms	27,80 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	62,00 ms	22,00 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,50 ms	-57,50 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	36,70 ms	-58,30 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	48,30 ms	18,30 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,012 s	12,00 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	37,90 ms	-57,10 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	36,90 ms	-58,10 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	No trip after boot (Grp2)						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

-----Group end:loCT 5A & 5A (265&265M)-----

-----Group:loCT 1A & 1A (265&265M)-----

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io1CT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: Io2CT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 17:17:47
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 17:17:53
Manager:

Vampset: 50N/51N

Test State:

Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 08-joulu-2014 17:19:47
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp

Version: 3.00 SR 2
Test End: 08-joulu-2014 17:21:03
Manager:

Test Settings

General

No. of ramp states: 6
Total steps per test: 506
Total time per test: 27,200
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I² / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I ²	10,00 mA -7,00 ° 50,000 Hz	10,00 mA -7,00 ° 50,000 Hz	40,00 mA -7,00 ° 50,000 Hz	360,0 mA 172,00 ° 50,000 Hz	360,0 mA 172,00 ° 50,000 Hz	420,0 mA 172,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	10,00 mA	10,00 mA	40,00 mA	360,0 mA	360,0 mA	420,0 mA
Sig 1 To	10,00 mA	40,00 mA	10,00 mA	360,0 mA	420,0 mA	360,0 mA
Sig 1 Delta	0,000 A	200,0 µA	-200,0 µA	0,000 A	600,0 µA	-600,0 µA
Sig 1 d/dt	0,000 A/s	4,000 mA/s	-4,000 mA/s	0,000 A/s	12,00 mA/s	-12,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	50,00 ms	50,00 ms
Ramp Steps	1	151	151	1	101	101
Ramp Time	1,000s	7,550s	7,550s	1,000s	5,050s	5,050s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping Version: 3.00 SR 2
Test Start: 08-joulu-2014 17:22:59 Test End: 08-joulu-2014 17:22:59
User Name: Jesse Saastamoinen Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I ²	20,00 mA	21,40 mA	2,000 mA	2,000 mA	1,400 mA	+	14,90
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I ²	19,00 mA	20,20 mA	2,000 mA	2,000 mA	1,200 mA	+	26,70
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I ²	400,0 mA	399,6 mA	6,000 mA	6,000 mA	-400,0 µA	+	700,0
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I ²	380,0 mA	378,6 mA	6,000 mA	6,000 mA	-1,400 mA	+	26,90

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'2	0,000 A -120,00 ° 50,000 Hz	32,00 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz	409,0 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz	8,000 mA -120,00 ° 50,000 Hz
State	Cold boot #2	No trip after boot (Grp2)						
I'2	8,000 mA -120,00 ° 50,000 Hz	371,0 mA -120,00 ° 50,000 Hz						

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	08-joulu-2014 17:24:57	Test End:	08-joulu-2014 17:24:57
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	47,30 ms	17,30 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	51,00 ms	11,00 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,00 ms	-57,00 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,30 ms	-57,70 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	58,30 ms	28,30 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,022 s	21,60 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	38,30 ms	-56,70 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	37,40 ms	-57,60 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0

	Cold boot #2	No trip after boot (Grp2)							
Assess	+	+							
Tolerance	0,000 s	0,000 s							
Start (A1)	0	0							
Trip (T1)	0	0							

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: IoCalcCT=1A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

-----Group end:I_oCT 1A & 1A (265&265M)-----

-----Group end:Earth fault stage I_o>> (50N/51N)-----